

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Kanako KITAYAMA et al.

Group Art Unit: 2812

Application No.: 10/574,893

Filed: August 9, 2006

Docket No.: 127642

For: SEMICONDUCTOR DEVICE MANUFACTURING METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the reference listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. An English language Abstract of one or more non-English language reference is attached. See Reference 1.
- ☒ 3. Reference 1 corresponds to JP-A-2001-089859, which was previously cited in an Information Disclosure Statement filed on April 6, 2006.

Respectfully submitted,

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Date: May 2, 2007

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DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461
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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 127642		APPLICATION NO. 10/574,893	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Kanakō KITAYAMA et al.			
				FILING DATE August 9, 2006		GROUP 2812	

U.S. PATENT DOCUMENTS				
Examiner Initials	Cite No.	Document Number	Date	Name

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
	1	KR 2001-0050510	06/15/2001	Korea	X	

OTHER DOCUMENTS		
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Date: May 2, 2007